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Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems

Embedded - System On Chip (SoC) refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

What are Embedded - System On Chip (SoC)?

System On Chip (SoC) integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

Details

Product Status	Active
Architecture	MCU, FPGA
Core Processor	Quad ARM® Cortex®-A53 MPCore™ with CoreSight™, Dual ARM®Cortex™-R5 with CoreSight™, ARM Mali™-400 MP2
Flash Size	-
RAM Size	256KB
Peripherals	DMA, WDT
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, MMC/SD/SDIO, SPI, UART/USART, USB OTG
Speed	500MHz, 600MHz, 1.2GHz
Primary Attributes	Zynq®UltraScale+™ FPGA, 926K+ Logic Cells
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1760-BBGA, FCBGA
Supplier Device Package	1760-FCBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xczu17eg-1ffvc1760i

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
V _{CCO_PSDDR}	PS DDR I/O supply voltage.	–0.500	1.650	V
V _{CC_PSDDR_PLL}	PS DDR PLL supply voltage.	–0.500	2.000	V
V _{CCO_PSIO}	PS I/O supply.	–0.500	3.630	V
V _{PSIN} ⁽²⁾	PS I/O input voltage.	–0.500	V _{CCO_PSIO} + 0.550	V
	PS DDR I/O input voltage.	–0.500	V _{CCO_PSDDR} + 0.550	V
V _{CC_PSBATT}	PS battery-backed RAM and battery-backed real-time clock (RTC) supply voltage.	–0.500	2.000	V
Programmable Logic (PL)				
V _{CCINT}	Internal supply voltage.	–0.500	1.000	V
V _{CCINT_IO} ⁽³⁾	Internal supply voltage for the I/O banks.	–0.500	1.000	V
V _{CCAUX}	Auxiliary supply voltage.	–0.500	2.000	V
V _{CCBRAM}	Supply voltage for the block RAM memories.	–0.500	1.000	V
V _{CCO}	Output drivers supply voltage for HD I/O banks.	–0.500	3.400	V
	Output drivers supply voltage for HP I/O banks.	–0.500	2.000	V
V _{CCAUX_IO} ⁽⁴⁾	Auxiliary supply voltage for the I/O banks.	–0.500	2.000	V
V _{REF}	Input reference voltage.	–0.500	2.000	V
V _{IN} ⁽²⁾⁽⁵⁾⁽⁷⁾	I/O input voltage for HD I/O banks. ⁽⁶⁾	–0.550	V _{CCO} + 0.550	V
	I/O input voltage for HP I/O banks.	–0.550	V _{CCO} + 0.550	V
I _{DC}	Available output current at the pad.	–20	20	mA
I _{RMS}	Available RMS output current at the pad.	–20	20	mA
GTH or GTY Transceiver				
V _{MGTAVCC}	Analog supply voltage for transceiver circuits.	–0.500	1.000	V
V _{MGTAVTT}	Analog supply voltage for transceiver termination circuits.	–0.500	1.300	V
V _{MGTVCCAUX}	Auxiliary analog Quad PLL (QPLL) voltage supply for transceivers.	–0.500	1.900	V
V _{MGTREFCLK}	Transceiver reference clock absolute input voltage.	–0.500	1.300	V
V _{MGTAVTTRCAL}	Analog supply voltage for the resistor calibration circuit of the transceiver column.	–0.500	1.300	V
V _{IN}	Receiver (RXP/RXN) and transmitter (TXP/TXN) absolute input voltage.	–0.500	1.200	V
I _{DCIN-FLOAT}	DC input current for receiver input pins DC coupled RX termination = floating. ⁽⁸⁾	–	10	mA
I _{DCIN-MGTAVTT}	DC input current for receiver input pins DC coupled RX termination = V _{MGTAVTT} .	–	10	mA
I _{DCIN-GND}	DC input current for receiver input pins DC coupled RX termination = GND. ⁽⁹⁾	–	0	mA
I _{DCIN-PROG}	DC input current for receiver input pins DC coupled RX termination = programmable. ⁽¹⁰⁾	–	0	mA
I _{DCOUT-FLOAT}	DC output current for transmitter pins DC coupled RX termination = floating.	–	6	mA
I _{DCOUT-MGTAVTT}	DC output current for transmitter pins DC coupled RX termination = V _{MGTAVTT} .	–	6	mA

V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot

Table 6: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HD I/O Banks⁽¹⁾

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
$V_{CCO} + 0.30$	100%	-0.30	100%
$V_{CCO} + 0.35$	100%	-0.35	90%
$V_{CCO} + 0.40$	100%	-0.40	78%
$V_{CCO} + 0.45$	100%	-0.45	40%
$V_{CCO} + 0.50$	100%	-0.50	24%
$V_{CCO} + 0.55$	100%	-0.55	18.0%
$V_{CCO} + 0.60$	100%	-0.60	13.0%
$V_{CCO} + 0.65$	100%	-0.65	10.8%
$V_{CCO} + 0.70$	92%	-0.70	9.0%
$V_{CCO} + 0.75$	92%	-0.75	7.0%
$V_{CCO} + 0.80$	92%	-0.80	6.0%
$V_{CCO} + 0.85$	92%	-0.85	5.0%
$V_{CCO} + 0.90$	92%	-0.90	4.0%
$V_{CCO} + 0.95$	92%	-0.95	2.5%

Notes:

1. A total of 200 mA per bank should not be exceeded.

Table 7: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HP I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
$V_{CCO} + 0.30$	100%	-0.30	100%
$V_{CCO} + 0.35$	100%	-0.35	100%
$V_{CCO} + 0.40$	92%	-0.40	92%
$V_{CCO} + 0.45$	50%	-0.45	50%
$V_{CCO} + 0.50$	20%	-0.50	20%
$V_{CCO} + 0.55$	10%	-0.55	10%
$V_{CCO} + 0.60$	6%	-0.60	6%
$V_{CCO} + 0.65$	2%	-0.65	2%
$V_{CCO} + 0.70$	2%	-0.70	2%

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μs .

PS-PL Power Sequencing

The PS and PL power supplies are fully independent. All PS power supplies can be powered before or after any PL power supplies. The PS and PL power regions are isolated to prevent damage.

Power Supply Requirements

Table 10 shows the minimum current, in addition to I_{CCQ} maximum, required by each Zynq UltraScale+ device for proper power-on and configuration. If the current minimums shown in Table 10 are met, the device powers on after all supplies have passed through their power-on reset threshold voltages. The device must not be configured until after V_{CCINT} is applied. Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

Table 10: Power-on Current by Device⁽¹⁾

I_{CC} Min =	I_{CCQ} +	XCZU2	XCZU3	XCZU4	XCZU5	XCZU6	XCZU7	XCZU9	XCZU11	XCZU15	XCZU17	XCZU19	Units
$I_{CCINTMIN}$	I_{CCINTQ}^{+}	464	464	770	770	1800	1514	1800	1961	2242	3433	3433	mA
$I_{CCINT_IOMIN}^{+}$ $I_{CCBRAMMIN}$	$I_{CCBRAMQ}^{+}$ $I_{CCINT_IOQ}^{+}$	155	155	257	257	600	505	600	654	748	1145	1145	mA
I_{CCOMIN}	I_{CCOQ}^{+}	50	50	50	50	50	50	50	55	63	96	96	mA
$I_{CCAUXMIN}^{+}$ I_{CCAUX_IOMIN}	I_{CCAUXQ}^{+} $I_{CCAUX_IOQ}^{+}$	111	111	386	386	650	362	650	709	810	1240	1240	mA

Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at www.xilinx.com/power) to estimate power-on current for all supplies.

Table 11 shows the power supply ramp time.

Table 11: Power Supply Ramp Time

Symbol	Description	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 95% of V_{CCINT} .	0.2	40	ms
T_{VCCINT_IO}	Ramp time from GND to 95% of V_{CCINT_IO} .	0.2	40	ms
T_{VCCINT_VCU}	Ramp time from GND to 95% of V_{CCINT_VCU} .	0.2	40	ms
T_{VCCO}	Ramp time from GND to 95% of V_{CCO} .	0.2	40	ms
T_{VCCAUX}	Ramp time from GND to 95% of V_{CCAUX} .	0.2	40	ms
$T_{VCCBRAM}$	Ramp time from GND to 95% of V_{CCBRAM} .	0.2	40	ms
$T_{MGTAVCC}$	Ramp time from GND to 95% of $V_{MGTAVCC}$.	0.2	40	ms
$T_{MGTAVTT}$	Ramp time from GND to 95% of $V_{MGTAVTT}$.	0.2	40	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 95% of $V_{MGTVCCAUX}$.	0.2	40	ms
$T_{VCC_PSINTFP}$	Ramp time from GND to 95% of $V_{CC_PSINTFP}$.	0.2	40	ms
$T_{VCC_PSINTLP}$	Ramp time from GND to 95% of $V_{CC_PSINTLP}$.	0.2	40	ms
T_{VCC_PSAUX}	Ramp time from GND to 95% of V_{CC_PSAUX} .	0.2	40	ms
$T_{VCC_PSINTFP_DDR}$	Ramp time from GND to 95% of $V_{CC_PSINTFP_DDR}$.	0.2	40	ms
T_{VCC_PSADC}	Ramp time from GND to 95% of V_{CC_PSADC} .	0.2	40	ms
T_{VCC_PSPLL}	Ramp time from GND to 95% of V_{CC_PSPLL} .	0.2	40	ms
$T_{PS_MGTRAVCC}$	Ramp time from GND to 95% of $V_{CC_MGTRAVCC}$.	0.2	40	ms
$T_{PS_MGTRAVTT}$	Ramp time from GND to 95% of $V_{CC_MGTRAVTT}$.	0.2	40	ms

Table 15: SelectIO DC Input and Output Levels for HP I/O Banks⁽¹⁾⁽²⁾⁽³⁾

I/O Standard	V _{IL}		V _{IH}		V _{OL}	V _{OH}	I _{OL}	I _{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
HSTL_I	−0.300	V _{REF} − 0.100	V _{REF} + 0.100	V _{CCO} + 0.300	0.400	V _{CCO} − 0.400	5.8	−5.8
HSTL_I_12	−0.300	V _{REF} − 0.080	V _{REF} + 0.080	V _{CCO} + 0.300	25% V _{CCO}	75% V _{CCO}	4.1	−4.1
HSTL_I_18	−0.300	V _{REF} − 0.100	V _{REF} + 0.100	V _{CCO} + 0.300	0.400	V _{CCO} − 0.400	6.2	−6.2
HSUL_12	−0.300	V _{REF} − 0.130	V _{REF} + 0.130	V _{CCO} + 0.300	20% V _{CCO}	80% V _{CCO}	0.1	−0.1
LVC MOS12	−0.300	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.300	0.400	V _{CCO} − 0.400	Note 4	Note 4
LVC MOS15	−0.300	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.300	0.450	V _{CCO} − 0.450	Note 5	Note 5
LVC MOS18	−0.300	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.300	0.450	V _{CCO} − 0.450	Note 5	Note 5
LVDCI_15	−0.300	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.300	0.450	V _{CCO} − 0.450	7.0	−7.0
LVDCI_18	−0.300	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.300	0.450	V _{CCO} − 0.450	7.0	−7.0
SSTL12	−0.300	V _{REF} − 0.100	V _{REF} + 0.100	V _{CCO} + 0.300	V _{CCO} /2 − 0.150	V _{CCO} /2 + 0.150	8.0	−8.0
SSTL135	−0.300	V _{REF} − 0.090	V _{REF} + 0.090	V _{CCO} + 0.300	V _{CCO} /2 − 0.150	V _{CCO} /2 + 0.150	9.0	−9.0
SSTL15	−0.300	V _{REF} − 0.100	V _{REF} + 0.100	V _{CCO} + 0.300	V _{CCO} /2 − 0.175	V _{CCO} /2 + 0.175	10.0	−10.0
SSTL18_I	−0.300	V _{REF} − 0.125	V _{REF} + 0.125	V _{CCO} + 0.300	V _{CCO} /2 − 0.470	V _{CCO} /2 + 0.470	7.0	−7.0
MIPI_DPHY_DCI_LP ⁽⁶⁾	−0.300	0.550	0.880	V _{CCO} + 0.300	0.050	1.100	0.01	−0.01

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).
3. POD10 and POD12 DC input and output levels are shown in [Table 16](#), [Table 20](#), [Table 21](#), and [Table 22](#).
4. Supported drive strengths of 2, 4, 6, or 8 mA in HP I/O banks.
5. Supported drive strengths of 2, 4, 6, 8, or 12 mA in HP I/O banks.
6. Low-power option for MIPI_DPHY_DCI.

Table 16: DC Input Levels for Single-ended POD10 and POD12 I/O Standards⁽¹⁾⁽²⁾

I/O Standard	V _{IL}		V _{IH}	
	V, Min	V, Max	V, Min	V, Max
POD10	−0.300	V _{REF} − 0.068	V _{REF} + 0.068	V _{CCO} + 0.300
POD12	−0.300	V _{REF} − 0.068	V _{REF} + 0.068	V _{CCO} + 0.300

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 19: Complementary Differential SelectIO DC Input and Output Levels for HP I/O Banks⁽¹⁾

I/O Standard	V_{ICM} (V) ⁽²⁾			V_{ID} (V) ⁽³⁾		V_{OL} (V) ⁽⁴⁾	V_{OH} (V) ⁽⁵⁾	I_{OL}	I_{OH}
	Min	Typ	Max	Min	Max	Max	Min	mA	mA
DIFF_HSTL_I	0.680	$V_{CCO}/2$	$(V_{CCO}/2) + 0.150$	0.100	–	0.400	$V_{CCO} - 0.400$	5.8	–5.8
DIFF_HSTL_I_12	$0.400 \times V_{CCO}$	$V_{CCO}/2$	$0.600 \times V_{CCO}$	0.100	–	$0.250 \times V_{CCO}$	$0.750 \times V_{CCO}$	4.1	–4.1
DIFF_HSTL_I_18	$(V_{CCO}/2) - 0.175$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.175$	0.100	–	0.400	$V_{CCO} - 0.400$	6.2	–6.2
DIFF_HSUL_12	$(V_{CCO}/2) - 0.120$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.120$	0.100	–	$20\% V_{CCO}$	$80\% V_{CCO}$	0.1	–0.1
DIFF_SSTL12	$(V_{CCO}/2) - 0.150$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.150$	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	8.0	–8.0
DIFF_SSTL135	$(V_{CCO}/2) - 0.150$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.150$	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	9.0	–9.0
DIFF_SSTL15	$(V_{CCO}/2) - 0.175$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.175$	0.100	–	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	10.0	–10.0
DIFF_SSTL18_I	$(V_{CCO}/2) - 0.175$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.175$	0.100	–	$(V_{CCO}/2) - 0.470$	$(V_{CCO}/2) + 0.470$	7.0	–7.0

Notes:

1. DIFF_POD10 and DIFF_POD12 HP I/O bank specifications are shown in Table 20, Table 21, and Table 22.
2. V_{ICM} is the input common mode voltage.
3. V_{ID} is the input differential voltage.
4. V_{OL} is the single-ended low-output voltage.
5. V_{OH} is the single-ended high-output voltage.

Table 20: DC Input Levels for Differential POD10 and POD12 I/O Standards⁽¹⁾⁽²⁾

I/O Standard	V_{ICM} (V)			V_{ID} (V)	
	Min	Typ	Max	Min	Max
DIFF_POD10	0.63	0.70	0.77	0.14	–
DIFF_POD12	0.76	0.84	0.92	0.16	–

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* (UG571).

Table 21: DC Output Levels for Single-ended and Differential POD10 and POD12 Standards⁽¹⁾⁽²⁾

Symbol	Description	V_{OUT}	Min	Typ	Max	Units
R_{OL}	Pull-down resistance.	V_{OM_DC} (as described in Table 22)	36	40	44	Ω
R_{OH}	Pull-up resistance.	V_{OM_DC} (as described in Table 22)	36	40	44	Ω

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* (UG571).

Table 22: Table 21 Definitions for DC Output Levels for POD Standards

Symbol	Description	All Speed Grades	Units
V_{OM_DC}	DC output Mid measurement level (for IV curve linearity).	$0.8 \times V_{CCO}$	V

Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 27 lists the production released Zynq UltraScale+ MPSoC, speed grade, and the minimum corresponding supported speed specification version and Vivado software revisions. The Vivado software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 27: Zynq UltraScale+ MPSoC Device Production Software and Speed Specification Release

Device	Speed Grade and V _{CCINT} Operating Voltages						
	0.90V	0.85V				0.72V	
	-3	-2	-1	-2L	-1L	-2L	-1L
XCZU2CG	N/A	Vivado tools 2017.1 v1.10					
XCZU2EG	N/A	Vivado tools 2017.1 v1.10					
XCZU3CG	N/A	Vivado tools 2017.1 v1.10					
XCZU3EG	N/A	Vivado tools 2017.1 v1.10					
XCZU4CG	N/A						
XCZU4EG							
XCZU4EV							
XCZU5CG	N/A						
XCZU5EG							
XCZU5EV							
XCZU6CG	N/A	Vivado tools 2017.1 v1.10					
XCZU6EG		Vivado tools 2017.1 v1.10					
XCZU7CG	N/A						
XCZU7EG							
XCZU7EV							
XCZU9CG	N/A	Vivado tools 2017.1 v1.10					
XCZU9EG		Vivado tools 2017.1 v1.10					
XCZU11EG							
XCZU15EG							
XCZU17EG							
XCZU19EG							

Notes:

1. See Table 3 for the complete list of operating voltages by speed grade.
2. Blank entries indicate a device and/or speed grade in Advance or Preliminary status.

Table 42: Linear Quad-SPI Interface⁽¹⁾

Symbol	Description	Load Conditions ⁽²⁾	Min	Max	Units
Quad-SPI device clock frequency operating at 100 MHz. Loopback enabled. LVCMOS 1.8V I/O standard.					
T _{DCQSPICLK5}	Quad-SPI clock duty cycle.	15 pF	45	55	%
		30 pF	45	55	%
T _{QSPISSCLK5}	Slave select asserted to next clock edge. ⁽³⁾	15 pF	5.0	–	ns
		30 pF	5.0	–	ns
T _{QSPISCLKSS5}	Clock edge to slave select deasserted.	15 pF	5.0	–	ns
		30 pF	5.0	–	ns
T _{QSPICKO5}	Clock to output delay, all outputs.	15 pF	3.2	7.4	ns
		30 pF	3.2	7.4	ns
T _{QSPIDCK5}	Setup time, all inputs.	15 pF	2.4	–	ns
		30 pF	2.4	–	ns
T _{QSPICKD5}	Hold time, all inputs.	15 pF	0.0	–	ns
		30 pF	0.0	–	ns
F _{QSPIREFCLK5}	Quad-SPI reference clock frequency.	15 pF	–	200	MHz
		30 pF	–	200	MHz
F _{QSPICLK5}	Quad-SPI device clock frequency.	15 pF	–	100	MHz
		30 pF	–	100	MHz

Notes:

1. The test conditions are configured for the linear Quad-SPI interface at 100 MHz with a 12 mA drive strength and fast slew rate.
2. 30 pF loads are for stacked modes.
3. T_{QSPISSCLK5} is only valid when two reference clock cycles are programmed between chip select and clock.

PS USB Interface

Table 43: ULPI Interface⁽¹⁾

Symbol	Description	Min	Max	Units
T _{ULPIDCK}	Input setup to ULPI clock, all inputs.	4.5	–	ns
T _{ULPICKD}	Input hold to ULPI clock, all inputs.	0	–	ns
T _{ULPICKO}	ULPI clock to output valid, all outputs.	2.0	8.86	ns
F _{ULPICLK}	ULPI reference clock frequency.	–	60	MHz

Notes:

1. The test conditions are configured to the LVCMOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

PS SPI Controller Interface

Table 48: SPI Interfaces⁽¹⁾

Symbol	Description	Min	Max	Units
SPI Master Interface				
$T_{DCMSPICLK}$	SPI master mode clock duty cycle.	45	55	%
$T_{MSPISSCLK}$	Slave select asserted to first active clock edge.	1 ⁽²⁾	–	$F_{SPI_REF_CLK}$ cycles
$T_{MSPISCLKSS}$	Last active clock edge to slave select deasserted.	1 ⁽²⁾	–	$F_{SPI_REF_CLK}$ cycles
$T_{MSPIDCK}$	Input setup time for MISO.	–2.0	–	ns
$T_{MSPICKD}$	Input hold time for MISO.	0.3	–	$F_{MSPICLK}$ cycles
$T_{MSPICKO}$	MOSI and slave select clock to out delay.	–2.0	5.0	ns
$F_{MSPICLK}$	SPI master device clock frequency.	–	50	MHz
$F_{SPI_REF_CLK}$	SPI reference clock frequency.	–	200	MHz
SPI Slave Interface				
$T_{SSPISSCLK}$	Slave select asserted to first active clock edge.	2	–	$F_{SPI_REF_CLK}$ cycles
$T_{SSPISCLKSS}$	Last active clock edge to slave select deasserted.	2	–	$F_{SPI_REF_CLK}$ cycles
$T_{SSPIDCK}$	Input setup time for MOSI.	5.0	–	ns
$T_{SSPICKD}$	Input hold time for MOSI.	1	–	$F_{SPI_REF_CLK}$ cycles
$T_{SSPICKO}$	MISO clock to out delay.	0.0	13.0	ns
$F_{SSPICKLK}$	SPI slave mode device clock frequency.	–	25	MHz
$F_{SPI_REF_CLK}$	SPI reference clock frequency.	–	200	MHz

Notes:

1. The test conditions are configured to the LVCMOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 30 pF load.
2. Valid when two SPI_REF_CLK delays are programmed between CS and CLK for $T_{MSPISSCLK}$, and between CLK and CS for $T_{MSPISCLKSS}$ in the SPI delay_reg0 register.

PS CAN Controller Interface

Table 49: CAN Interface⁽¹⁾

Symbol	Description	Min	Max	Units
$T_{PWCANRX}$	Receive pulse width.	1.0	–	μs
$T_{PWCANTX}$	Transmit pulse width.	1.0	–	μs
$F_{CAN_REF_CLK}$	Internally sourced CAN reference clock frequency.	–	100	MHz
	Externally sourced CAN reference clock frequency.	–	40	MHz

Notes:

1. The test conditions are configured to the LVCMOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

Programmable Logic (PL) Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Zynq UltraScale+ MPSoC. These values are subject to the same guidelines as the [AC Switching Characteristics, page 22](#). In each table, the I/O bank type is either high performance (HP) or high density (HD).

Table 70: LVDS Component Mode Performance

Description	I/O Bank Type	Speed Grade and V _{CCINT} Operating Voltages										Units
		0.90V		0.85V				0.72V				
		-3		-2		-1		-2		-1		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
LVDS TX DDR (OSERDES 4:1, 8:1)	HP	0	1250	0	1250	0	1250	0	1250	0	1250	Mb/s
LVDS TX SDR (OSERDES 2:1, 4:1)	HP	0	625	0	625	0	625	0	625	0	625	Mb/s
LVDS RX DDR (ISERDES 1:4, 1:8) ⁽¹⁾	HP	0	1250	0	1250	0	1250	0	1250	0	1250	Mb/s
LVDS RX DDR	HD	0	250	0	250	0	250	0	250	0	250	Mb/s
LVDS RX SDR (ISERDES 1:2, 1:4) ⁽¹⁾	HP	0	625	0	625	0	625	0	625	0	625	Mb/s
LVDS RX SDR	HD	0	125	0	125	0	125	0	125	0	125	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 71: LVDS Native Mode Performance⁽¹⁾⁽²⁾

Description	DATA_WIDTH	I/O Bank Type	Speed Grade and V _{CCINT} Operating Voltages										Units
			0.90V		0.85V				0.72V				
			-3 ⁽³⁾		-2 ⁽³⁾		-1		-2 ⁽³⁾		-1		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
LVDS TX DDR (TX_BITSLICE)	4	HP	375	1600	375	1600	375	1260	375	1400	375	1260	Mb/s
	8		375	1600	375	1600	375	1260	375	1600	375	1260	Mb/s
LVDS TX SDR (TX_BITSLICE)	4	HP	187.5	800	187.5	800	187.5	630	187.5	700	187.5	630	Mb/s
	8		187.5	800	187.5	800	187.5	630	187.5	800	187.5	630	Mb/s
LVDS RX DDR (RX_BITSLICE) ⁽⁴⁾	4	HP	375	1600	375	1600	375	1260	375	1400	375	1260	Mb/s
	8		375	1600	375	1600	375	1260	375	1600	375	1260	Mb/s
LVDS RX SDR (RX_BITSLICE) ⁽⁴⁾	4	HP	187.5	800	187.5	800	187.5	630	187.5	700	187.5	630	Mb/s
	8		187.5	800	187.5	800	187.5	630	187.5	800	187.5	630	Mb/s

Notes:

1. Native mode is supported through the [High-Speed SelectIO Interface Wizard](#) available with the Vivado Design Suite. The performance values assume a source-synchronous interface.
2. PLL settings can restrict the minimum allowable data rate. For example, when using the PLL with CLKOUTPHY_MODE = VCO_HALF the minimum frequency is PLL_F_{VCOMIN}/2.
3. In the SBVA484 package, the maximum data rate is 1260 Mb/s for DDR interfaces and 630 Mb/s for SDR interfaces.
4. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 74: Maximum Physical Interface (PHY) Rate for Memory Interfaces (Cont'd)

Memory Standard	Package ⁽¹⁾	DRAM Type	Speed Grade and V _{CCINT} Operating Voltages					Units
			0.90V	0.85V		0.72V		
			-3	-2	-1	-2	-1	
DDR3L	All FFV packages and FBVB900	Single rank component	1866	1866	1866	1866	1600	Mb/s
		1 rank DIMM ⁽²⁾⁽³⁾	1600	1600	1600	1600	1333	Mb/s
		2 rank DIMM ⁽²⁾⁽⁵⁾	1333	1333	1333	1333	1066	Mb/s
		4 rank DIMM ⁽²⁾⁽⁶⁾	800	800	800	800	606	Mb/s
	SFVC784	Single rank component	1600	1600	1600	1600	1600	Mb/s
		1 rank DIMM ⁽²⁾⁽³⁾	1600	1600	1600	1600	1333	Mb/s
		2 rank DIMM ⁽²⁾⁽⁵⁾	1333	1333	1333	1333	1066	Mb/s
		4 rank DIMM ⁽²⁾⁽⁶⁾	800	800	800	800	606	Mb/s
QDR II +	All	Single rank component ⁽⁷⁾	633	633	600	600	550	MHz
RLDRAM 3	All FFV packages and FBVB900	Single rank component	1200	1200	1066	1066	933	MHz
	SFVC784	Single rank component	1066	1066	933	933	800	MHz
QDR IV XP	All	Single rank component	1066	1066	1066	933	933	MHz
LPDDR3	All	Single rank component	1600	1600	1600	1600	1600	Mb/s

Notes:

1. The SBVA484 and SFVA625 packages do not support the PL memory interfaces.
2. Dual in-line memory module (DIMM) includes RDIMM, SODIMM, UDIMM, and LRDIMM.
3. Includes: 1 rank 1 slot, DDP 2 rank, LRDIMM 2 or 4 rank 1 slot.
4. For the DDR4 DDP components at -3 and -2 speed grades and V_{CCINT} = 0.85V, the maximum data rate is 2133 Mb/s for six or more DDP devices. For five or less DDP devices, use the single rank DIMM data rates for the -3 and -2 speed grades at 0.85V.
5. Includes: 2 rank 1 slot, 1 rank 2 slot, LRDIMM 2 rank 2 slot.
6. Includes: 2 rank 2 slot, 4 rank 1 slot.
7. The QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations.

Programmable Logic (PL) Switching Characteristics

Table 75 (high-density IOB (HD)) and Table 76 (high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- $T_{\text{INBUF_DELAY_PAD_I}}$ is the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- $T_{\text{OUTBUF_DELAY_O_PAD}}$ is the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- $T_{\text{OUTBUF_DELAY_TD_PAD}}$ is the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than $T_{\text{OUTBUF_DELAY_TD_PAD}}$ when the DCITERMDISABLE pin is used. In HD I/O banks, the on-die termination turn-on time is always faster than $T_{\text{OUTBUF_DELAY_TD_PAD}}$ when the INTERMDISABLE pin is used.

IOB High Density (HD) Switching Characteristics

Table 75: IOB High Density (HD) Switching Characteristics

I / O Standards	$T_{\text{INBUF_DELAY_PAD_I}}$					$T_{\text{OUTBUF_DELAY_O_PAD}}$					$T_{\text{OUTBUF_DELAY_TD_PAD}}$					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
DIFF_HSTL_I_18_F	0.978	0.978	1.058	0.978	1.058	1.574	1.574	1.718	1.574	1.718	1.160	1.160	1.271	1.160	1.271	ns
DIFF_HSTL_I_18_S	0.978	0.978	1.058	0.978	1.058	1.805	1.805	1.950	1.805	1.950	1.748	1.748	1.867	1.748	1.867	ns
DIFF_HSTL_I_F	0.978	0.978	1.058	0.978	1.058	1.611	1.611	1.762	1.611	1.762	1.313	1.313	1.417	1.313	1.417	ns
DIFF_HSTL_I_S	0.978	0.978	1.058	0.978	1.058	1.798	1.798	1.913	1.798	1.913	1.630	1.630	1.780	1.630	1.780	ns
DIFF_HSUL_12_F	0.911	0.911	0.977	0.911	0.977	1.573	1.573	1.703	1.573	1.703	1.222	1.222	1.335	1.222	1.335	ns
DIFF_HSUL_12_S	0.911	0.911	0.977	0.911	0.977	1.711	1.711	1.864	1.711	1.864	1.536	1.536	1.665	1.536	1.665	ns
DIFF_SSTL12_F	0.906	0.906	0.977	0.906	0.977	1.643	1.643	1.792	1.643	1.792	1.285	1.285	1.423	1.285	1.423	ns
DIFF_SSTL12_S	0.906	0.906	0.977	0.906	0.977	1.784	1.784	1.948	1.784	1.948	1.567	1.567	1.706	1.567	1.706	ns
DIFF_SSTL135_F	0.927	0.927	0.995	0.927	0.995	1.625	1.625	1.765	1.625	1.765	1.341	1.341	1.458	1.341	1.458	ns
DIFF_SSTL135_II_F	0.927	0.927	0.995	0.927	0.995	1.623	1.623	1.770	1.623	1.770	1.325	1.325	1.470	1.325	1.470	ns
DIFF_SSTL135_II_S	0.927	0.927	0.995	0.927	0.995	1.768	1.768	1.916	1.768	1.916	1.722	1.722	1.911	1.722	1.911	ns
DIFF_SSTL135_S	0.927	0.927	0.995	0.927	0.995	1.869	1.869	2.025	1.869	2.025	1.814	1.814	1.976	1.814	1.976	ns
DIFF_SSTL15_F	0.928	0.928	1.020	0.928	1.020	1.628	1.628	1.771	1.628	1.771	1.374	1.374	1.483	1.374	1.483	ns
DIFF_SSTL15_II_F	0.928	0.928	1.020	0.928	1.020	1.622	1.622	1.778	1.622	1.778	1.356	1.356	1.442	1.356	1.442	ns
DIFF_SSTL15_II_S	0.928	0.928	1.020	0.928	1.020	1.821	1.821	1.987	1.821	1.987	1.895	1.895	2.047	1.895	2.047	ns
DIFF_SSTL15_S	0.928	0.928	1.020	0.928	1.020	1.824	1.824	1.977	1.824	1.977	1.743	1.743	1.907	1.743	1.907	ns
DIFF_SSTL18_II_F	0.961	0.961	1.038	0.961	1.038	1.729	1.729	1.880	1.729	1.880	1.377	1.377	1.492	1.377	1.492	ns
DIFF_SSTL18_II_S	0.961	0.961	1.038	0.961	1.038	1.796	1.796	1.965	1.796	1.965	1.616	1.616	1.800	1.616	1.800	ns
DIFF_SSTL18_I_F	0.961	0.961	1.038	0.961	1.038	1.609	1.609	1.755	1.609	1.755	1.220	1.220	1.313	1.220	1.313	ns
DIFF_SSTL18_I_S	0.961	0.961	1.038	0.961	1.038	1.786	1.786	1.942	1.786	1.942	1.677	1.677	1.836	1.677	1.836	ns
HSTL_I_18_F	0.947	0.947	1.021	0.947	1.021	1.574	1.574	1.718	1.574	1.718	1.160	1.160	1.271	1.160	1.271	ns
HSTL_I_18_S	0.947	0.947	1.021	0.947	1.021	1.805	1.805	1.950	1.805	1.950	1.748	1.748	1.867	1.748	1.867	ns

Input Delay Measurement Methodology

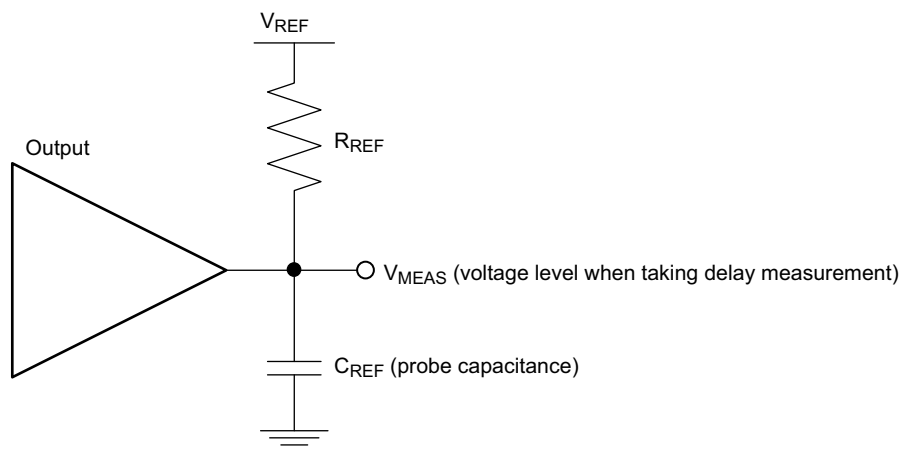
Table 78 shows the test setup parameters used for measuring input delay.

Table 78: Input Delay Measurement Methodology

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(6)}$	$V_{REF}^{(1)(3)(5)}$
LVC MOS, 1.2V	LVC MOS12	0.1	1.1	0.6	–
LVC MOS, LVDCI, HSLVDCI, 1.5V	LVC MOS15, LVDCI_15, HSLVDCI_15	0.1	1.4	0.75	–
LVC MOS, LVDCI, HSLVDCI, 1.8V	LVC MOS18, LVDCI_18, HSLVDCI_18	0.1	1.7	0.9	–
LVC MOS, 2.5V	LVC MOS25	0.1	2.4	1.25	–
LVC MOS, 3.3V	LVC MOS33	0.1	3.2	1.65	–
LVTTL, 3.3V	LVTTL	0.1	3.2	1.65	–
HSTL (high-speed transceiver logic), class I, 1.2V	HSTL_I_12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	V_{REF}	0.6
HSTL, class I, 1.5V	HSTL_I	$V_{REF} - 0.325$	$V_{REF} + 0.325$	V_{REF}	0.75
HSTL, class I, 1.8V	HSTL_I_18	$V_{REF} - 0.4$	$V_{REF} + 0.4$	V_{REF}	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	V_{REF}	0.6
SSTL12 (stub series terminated logic), 1.2V	SSTL12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	V_{REF}	0.6
SSTL135 and SSTL135 class II, 1.35V	SSTL135, SSTL135_II	$V_{REF} - 0.2875$	$V_{REF} + 0.2875$	V_{REF}	0.675
SSTL15 and SSTL15 class II, 1.5V	SSTL15, SSTL15_II	$V_{REF} - 0.325$	$V_{REF} + 0.325$	V_{REF}	0.75
SSTL18, class I and II, 1.8V	SSTL18_I, SSTL18_II	$V_{REF} - 0.4$	$V_{REF} + 0.4$	V_{REF}	0.9
POD10, 1.0V	POD10	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	0.7
POD12, 1.2V	POD12	$V_{REF} - 0.24$	$V_{REF} + 0.24$	V_{REF}	0.84
DIFF_HSTL, class I, 1.2V	DIFF_HSTL_I_12	$0.6 - 0.25$	$0.6 + 0.25$	0 ⁽⁶⁾	–
DIFF_HSTL, class I, 1.5V	DIFF_HSTL_I	$0.75 - 0.325$	$0.75 + 0.325$	0 ⁽⁶⁾	–
DIFF_HSTL, class I, 1.8V	DIFF_HSTL_I_18	$0.9 - 0.4$	$0.9 + 0.4$	0 ⁽⁶⁾	–
DIFF_HSUL, 1.2V	DIFF_HSUL_12	$0.6 - 0.25$	$0.6 + 0.25$	0 ⁽⁶⁾	–
DIFF_SSTL, 1.2V	DIFF_SSTL12	$0.6 - 0.25$	$0.6 + 0.25$	0 ⁽⁶⁾	–
DIFF_SSTL135 and DIFF_SSTL135 class II, 1.35V	DIFF_SSTL135, DIFF_SSTL135_II	$0.675 - 0.2875$	$0.675 + 0.2875$	0 ⁽⁶⁾	–
DIFF_SSTL15 and DIFF_SSTL15 class II, 1.5V	DIFF_SSTL15, DIFF_SSTL15_II	$0.75 - 0.325$	$0.75 + 0.325$	0 ⁽⁶⁾	–
DIFF_SSTL18_I, DIFF_SSTL18_II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	$0.9 - 0.4$	$0.9 + 0.4$	0 ⁽⁶⁾	–
DIFF_POD10, 1.0V	DIFF_POD10	$0.5 - 0.2$	$0.5 + 0.2$	0 ⁽⁶⁾	–
DIFF_POD12, 1.2V	DIFF_POD12	$0.6 - 0.25$	$0.6 + 0.25$	0 ⁽⁶⁾	–
LVDS (low-voltage differential signaling), 1.8V	LVDS	$0.9 - 0.125$	$0.9 + 0.125$	0 ⁽⁶⁾	–
LVDS_25, 2.5V	LVDS_25	$1.25 - 0.125$	$1.25 + 0.125$	0 ⁽⁶⁾	–

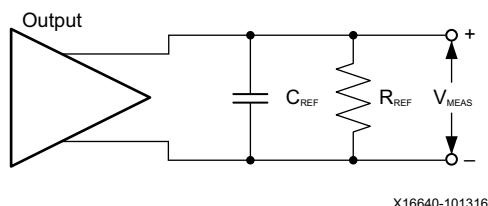
Output Delay Measurement Methodology

Output delays are measured with short output traces. Standard termination was used for all testing. The propagation delay of the trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in [Figure 1](#) and [Figure 2](#).



X16654-101316

Figure 1: Single-Ended Test Setup



X16640-101316

Figure 2: Differential Test Setup

Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using this method:

1. Simulate the output driver of choice into the generalized test setup using values from [Table 79](#).
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of [step 2](#) and [step 4](#). The increase or decrease in delay yields the actual propagation delay of the PCB trace.

UltraRAM Switching Characteristics

The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoC that include this memory.

Table 81: UltraRAM Switching Characteristics

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2	-1	-2	-1	
Maximum Frequency							
F _{MAX}	UltraRAM maximum frequency with OREG_B = True.	650	600	575	500	481	MHz
F _{MAX_ECC}	UltraRAM maximum frequency with OREG_B = False and EN_ECC_RD_B = True.	450	400	386	325	315	MHz
F _{MAX_NORPIPELINE}	UltraRAM maximum frequency with OREG_B = False and EN_ECC_RD_B = False.	550	500	478	425	408	MHz
T _{PW} ⁽¹⁾	Minimum pulse width.	650	700	730	800	832	ps
T _{RSTPW}	Asynchronous reset minimum pulse width. One cycle required.	1 clock cycle					

Notes:

1. The MMCM and PLL DUTY_CYCLE attribute should be set to 50% to meet the pulse-width requirements at the higher frequencies.

Input/Output Delay Switching Characteristics

Table 82: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2	-1	-2	-1	
F _{REFCLK}	REFCLK frequency for IDELAYCTRL (component mode).	300 to 800					MHz
	REFCLK frequency for BITSlice_CONTROL (native mode). ⁽¹⁾	300 to 2666.67	300 to 2666.67	300 to 2400	300 to 2400	300 to 2133	MHz
T _{MINPER_CLK}	Minimum period for IODELAY clock.	3.195	3.195	3.195	3.195	3.195	ns
T _{MINPER_RST}	Minimum reset pulse width.	52.00					ns
T _{IDELAY_RESOLUTION} / T _{ODELAY_RESOLUTION}	IDELAY/ODELAY chain resolution.	2.1 to 12					ps

Notes:

1. PLL settings could restrict the minimum allowable data rate. For example, when using a PLL with CLKOUTPHY_MODE = VCO_HALF, the minimum frequency is PLL_FVCOMIN/2.

MMCM Switching Characteristics

Table 85: MMCM Specification

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2	-1	-2	-1	
MMCM_F _{INMAX}	Maximum input clock frequency.	1066	933	800	933	800	MHz
MMCM_F _{INMIN}	Minimum input clock frequency.	10	10	10	10	10	MHz
MMCM_F _{INJITTER}	Maximum input clock period jitter.	< 20% of clock input period or 1 ns Max					
MMCM_F _{INDUTY}	Input duty cycle range: 10–49 MHz.	25–75					%
	Input duty cycle range: 50–199 MHz.	30–70					%
	Input duty cycle range: 200–399 MHz.	35–65					%
	Input duty cycle range: 400–499 MHz.	40–60					%
	Input duty cycle range: >500 MHz.	45–55					%
MMCM_F _{MIN_PSCLK}	Minimum dynamic phase shift clock frequency.	0.01	0.01	0.01	0.01	0.01	MHz
MMCM_F _{MAX_PSCLK}	Maximum dynamic phase shift clock frequency.	550	500	450	500	450	MHz
MMCM_F _{VCOMIN}	Minimum MMCM VCO frequency.	800	800	800	800	800	MHz
MMCM_F _{VCOMAX}	Maximum MMCM VCO frequency.	1600	1600	1600	1600	1600	MHz
MMCM_F _{BANDWIDTH}	Low MMCM bandwidth at typical. ⁽¹⁾	1.00	1.00	1.00	1.00	1.00	MHz
	High MMCM bandwidth at typical. ⁽¹⁾	4.00	4.00	4.00	4.00	4.00	MHz
MMCM_T _{STATPHAOFFSET}	Static phase offset of the MMCM outputs. ⁽²⁾	0.12	0.12	0.12	0.12	0.12	ns
MMCM_T _{OUTJITTER}	MMCM output jitter.	Note 3					
MMCM_T _{OUTDUTY}	MMCM output clock duty cycle precision. ⁽⁴⁾	0.165	0.20	0.20	0.20	0.20	ns
MMCM_T _{LOCKMAX}	MMCM maximum lock time for MMCM_F _{PFDMIN} .	100	100	100	100	100	μs
MMCM_F _{OUTMAX}	MMCM maximum output frequency.	891	775	667	725	667	MHz
MMCM_F _{OUTMIN}	MMCM minimum output frequency. ⁽⁴⁾⁽⁵⁾	6.25	6.25	6.25	6.25	6.25	MHz
MMCM_T _{EXTFDVAR}	External clock feedback variation.	< 20% of clock input period or 1 ns Max					
MMCM_RST _{MINPULSE}	Minimum reset pulse width.	5.00	5.00	5.00	5.00	5.00	ns
MMCM_F _{PFDMAX}	Maximum frequency at the phase frequency detector.	550	500	450	500	450	MHz
MMCM_F _{PFDMIN}	Minimum frequency at the phase frequency detector.	10	10	10	10	10	MHz
MMCM_T _{FBDELAY}	Maximum delay in the feedback path.	5 ns Max or one clock cycle					

Table 99: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F _{GCLK}	Reference clock frequency range.		60	–	820	MHz
T _{RCLK}	Reference clock rise time.	20% – 80%	–	200	–	ps
T _{FCLK}	Reference clock fall time.	80% – 20%	–	200	–	ps
T _{DCREF}	Reference clock duty cycle.	Transceiver PLL only	40	50	60	%

Table 100: GTH Transceiver Reference Clock Oscillator Selection Phase Noise Mask

Symbol	Description	Offset Frequency	Min	Typ	Max	Units
QPLL _{REFCLKMASK} ⁽¹⁾⁽²⁾	QPLL0/QPLL1 reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	–	–	–105	dBc/Hz
		100 kHz	–	–	–124	
		1 MHz	–	–	–130	
CPLL _{REFCLKMASK} ⁽¹⁾⁽²⁾	CPLL reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	–	–	–105	dBc/Hz
		100 kHz	–	–	–124	
		1 MHz	–	–	–130	
		50 MHz	–	–	–140	

Notes:

- For reference clock frequencies other than 312.5 MHz, adjust the phase-noise mask values by 20 x Log(N/312.5) where N is the new reference clock frequency in MHz.
- This reference clock phase-noise mask is superseded by any reference clock phase-noise mask that is specified in a supported protocol, e.g., PCIe.

Table 101: GTH Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T _{LOCK}	Initial PLL lock.		–	–	1	ms
T _{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	37 x 10 ⁶	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		–	50,000	2.3 x 10 ⁶	UI

Table 102: GTH Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Data Width Conditions (Bit)		Speed Grade and V _{CCINT} Operating Voltages					Units
				0.90V	0.85V		0.72V		
		Internal Logic	Interconnect Logic	-3(2)	-2(2)(3)	-1(4)(5)	-2(3)	-1(5)	
F _{TXOUTPMA}	TXOUTCLK maximum frequency sourced from OUTCLKPMA			511.719	511.719	390.625	390.625	322.266	MHz
F _{RXOUTPMA}	RXOUTCLK maximum frequency sourced from OUTCLKPMA			511.719	511.719	390.625	390.625	322.266	MHz

Table 103: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTHTX}	Serial data rate range		0.500	–	F _{GTHMAX}	Gb/s
T _{RTX}	TX rise time	20%–80%	–	21	–	ps
T _{FTX}	TX fall time	80%–20%	–	21	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	500.00	ps
T _{J16.375}	Total jitter ⁽²⁾⁽⁴⁾	16.375 Gb/s	–	–	0.28	UI
D _{J16.375}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J15.0}	Total jitter ⁽²⁾⁽⁴⁾	15.0 Gb/s	–	–	0.28	UI
D _{J15.0}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J14.1}	Total jitter ⁽²⁾⁽⁴⁾	14.1 Gb/s	–	–	0.28	UI
D _{J14.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J14.1}	Total jitter ⁽²⁾⁽⁴⁾	14.025 Gb/s	–	–	0.28	UI
D _{J14.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J13.1}	Total jitter ⁽²⁾⁽⁴⁾	13.1 Gb/s	–	–	0.28	UI
D _{J13.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J12.5_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	12.5 Gb/s	–	–	0.28	UI
D _{J12.5_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J12.5_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	12.5 Gb/s	–	–	0.33	UI
D _{J12.5_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J11.3_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	11.3 Gb/s	–	–	0.28	UI
D _{J11.3_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J10.3125_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.28	UI
D _{J10.3125_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J10.3125_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.33	UI
D _{J10.3125_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J9.953_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	9.953 Gb/s	–	–	0.28	UI
D _{J9.953_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J9.953_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	9.953 Gb/s	–	–	0.33	UI
D _{J9.953_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J8.0}	Total jitter ⁽³⁾⁽⁴⁾	8.0 Gb/s	–	–	0.32	UI
D _{J8.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J6.6}	Total jitter ⁽³⁾⁽⁴⁾	6.6 Gb/s	–	–	0.30	UI
D _{J6.6}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J5.0}	Total jitter ⁽³⁾⁽⁴⁾	5.0 Gb/s	–	–	0.30	UI
D _{J5.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J4.25}	Total jitter ⁽³⁾⁽⁴⁾	4.25 Gb/s	–	–	0.30	UI
D _{J4.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J4.0}	Total jitter ⁽³⁾⁽⁴⁾	4.0 Gb/s	–	–	0.32	UI
D _{J4.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.16	UI
T _{J3.20}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁵⁾	–	–	0.20	UI
D _{J3.20}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.10	UI

Table 115: GTY Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTYTX}	Serial data rate range		0.500	–	F _{GTYMAX}	Gb/s
T _{RTX}	TX rise time	20%–80%	–	21	–	ps
T _{FTX}	TX fall time	80%–20%	–	21	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	500.00	ps
T _{J32.75}	Total jitter ⁽²⁾⁽⁴⁾	32.75 Gb/s	–	–	0.35	UI
D _{J32.75}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.19	UI
T _{J28.21}	Total jitter ⁽²⁾⁽⁴⁾	28.21 Gb/s	–	–	0.28	UI
D _{J28.21}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J16.375}	Total jitter ⁽²⁾⁽⁴⁾	16.375 Gb/s	–	–	0.28	UI
D _{J16.375}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J15.0}	Total jitter ⁽²⁾⁽⁴⁾	15.0 Gb/s	–	–	0.28	UI
D _{J15.0}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J14.1}	Total jitter ⁽²⁾⁽⁴⁾	14.1 Gb/s	–	–	0.28	UI
D _{J14.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J14.1}	Total jitter ⁽²⁾⁽⁴⁾	14.025 Gb/s	–	–	0.28	UI
D _{J14.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J13.1}	Total jitter ⁽²⁾⁽⁴⁾	13.1 Gb/s	–	–	0.28	UI
D _{J13.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J12.5_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	12.5 Gb/s	–	–	0.28	UI
D _{J12.5_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J12.5_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	12.5 Gb/s	–	–	0.33	UI
D _{J12.5_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J11.3_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	11.3 Gb/s	–	–	0.28	UI
D _{J11.3_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J10.3125_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.28	UI
D _{J10.3125_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J10.3125_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.33	UI
D _{J10.3125_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J9.953_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	9.953 Gb/s	–	–	0.28	UI
D _{J9.953_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J9.953_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	9.953 Gb/s	–	–	0.33	UI
D _{J9.953_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J8.0}	Total jitter ⁽³⁾⁽⁴⁾	8.0 Gb/s	–	–	0.32	UI
D _{J8.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J6.6}	Total jitter ⁽³⁾⁽⁴⁾	6.6 Gb/s	–	–	0.30	UI
D _{J6.6}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J5.0}	Total jitter ⁽³⁾⁽⁴⁾	5.0 Gb/s	–	–	0.30	UI
D _{J5.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J4.25}	Total jitter ⁽³⁾⁽⁴⁾	4.25 Gb/s	–	–	0.30	UI
D _{J4.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI

Date	Version	Description of Revisions
02/10/2017	1.2	Updated some of the maximum voltages in the Processor System (PS) section and other specifications in the Programmable Logic (PL) and GTH or GTY Transceiver sections of Table 1 . Updated Table 2 , Table 4 , Table 6 , Table 7 , and Table 9 . Revised the Power Supply Sequencing section including Table 10 . Added PS and VCU ramp times to Table 11 . Revised V_{ODIFF} in Table 24 . Updated Table 25 . Added Note 1 to Table 26 . Table 30 replaces the previous three PS memory performance tables. Added values to Table 34 , Table 37 , and Table 38 . Deleted the waveforms in the PS Switching Characteristics section (Figures 1-16 and Figures 25-26). Revised values in the PS NAND Memory Controller Interface section. Added and updated data in Table 40 . Added Note 3 to Table 41 . Added Note 3 to Table 42 . Added Note 1 to Table 45 . Updated Table 48 and removed Note 3 . Added data to Table 56 . Updated Table 60 . Added Table 61 . Updated Table 63 . Revised Table 69 . Added data to Table 70 . Added Note 2 to Table 71 . Updated Table 74 and added Note 4 . Updated V_L and V_H values in Table 78 . Added T_{MINPER_CLK} , revised F_{REFCLK} , and Note 1 to Table 82 . Added $MMCM_F_{DPRCLK_MAX}$ to Table 85 and $PLL_F_{DPRCLK_MAX}$ to Table 86 . Added data to Table 94 , Table 96 , Table 98 , Table 101 , and updated the note references in Table 102 . Updated Table 103 and added Note 8 . Updated Table 104 and added Note 7 . Added more protocols, Note 1 and Note 2 to Table 105 . Removed the GTH Transceiver Protocol Jitter Characteristics section because it is covered in Table 105 . Added Note 1 to Table 109 . Added data to Table 106 , Table 108 , Table 110 , Table 113 . Added Note 2 to Table 112 . Added note references in Table 114 . Updated Table 115 and added Note 8 . Updated Table 116 and added Note 7 . Added more protocols and Note 3 to Table 117 . Removed the GTy Transceiver Protocol Jitter Characteristics section because it is covered in Table 117 . Revised Table 124 . Added T_{POR} and updated F_{ICAPCK} in Table 127 . Updated the Automotive Applications Disclaimer .
06/20/2016	1.1	Updated the Summary description. In Table 1 , revised V_{IN} for HP I/O banks and added clarifications to some descriptions and symbols. Added I_{RPU} , I_{RPD} , and Note 4 to Table 2 and updated $V_{PS_MGTRAVCC}$, the PL System Monitor section, and Note 3 and Note 5 . Updated Note 5 in Table 4 . Updated the PS Power-On/Off Power Supply Sequencing section including all the voltage supply names. Added $MIPI_DPHY_DCI$ to Table 14 , Table 15 , and Table 17 . Updated Table 23 , including removing the V_{CCO} specification and adding Note 1 . Added Note 1 to Table 24 . Updated Table 25 speed specifications for Vivado Design Suite 2016.1. Added values to Table 28 . Updated the -2 value in Table 29 . Added $F_{DPLIVEVIDEO}$ and updated $F_{FCIDMACLK}$ in Table 33 . Added VCO frequencies to Table 36 . Added the T_{PSPOR} minimum to Table 37 and updated Note 1 . Added Table 38 . Added value delineation over V_{CCINT} operating voltages in Table 39 . Revised values for F_{TCK} and T_{TAPTCK}/T_{TCKTAP} in Table 40 and added value delineation over V_{CCINT} operating voltages. Updated the PS NAND Memory Controller Interface section. Revised some units and Note 1 in Table 41 and Table 42 . Removed Figure 6: Quad-SPI Interface (Feedback Clock Disabled) Timing. Updated Note 1 of Table 43 . Added $F_{TSI_REF_CLK}$ to Table 44 and updated Note 1 . In Table 45 , revised $T_{DCSDHCLK1}$, $T_{DCSDHCLK2}$, and $T_{DCSDHCLK3}$ and Note 1 . In Table 46 , revised Note 1 . In Table 47 , revised Note 1 . Revised Table 48 , including Note 1 , and added Note 2 and Note 3 . In Table 49 , Table 50 , Table 51 , and Table 53 , revised Note 1 . Updated Table 71 . Replaced Table 74 . Updated Table 75 and Table 76 . Updated Table 78 and Table 79 . In Table 80 , added the Block RAM and FIFO Clock-to-Out Delays section. Updated the R_{IN} and C_{EXT} values in Table 57 and Table 95 . Updated the -2 (0.72V) and -1 (0.72V) values and added Note 1 to Table 97 . Added Table 100 and Table 112 . Added Note 2 to Table 106 . Revised data in Table 109 . Revised Table 114 . Revised data and added notes in the Integrated Interface Block for Interlaken section and Table 121 . Moved Table 123 . Revised INL in Table 124 . Added notes to Table 125 and Table 126 . In the eFUSE and Programming Conditions table, updated the I_{PSFS} description.
11/24/2015	1.0	Initial Xilinx release.

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